

Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V _{DSS}	60	V
Gate-Source Voltage			V _{GS}	±20	V
Continuous Drain Current	V _{GS} = 10V	(Note 6)	ID	3.5	
		T _A = +70°C (Note 6)		2.8	А
		(Note 5)		2.8	
Pulsed Drain Current	V_{GS} = 10V	(Note 7)	I _{DM}	16	А
Continuous Source Current (Body Diode) (Note 6)		Is	2.6	А	
Pulsed Source Current (Body Diode) (Note 7)		I _{SM}	16	А	

Thermal Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit		
Power Dissipation	(Note 5)		1.1 8.8	W	
Linear Derating Factor	(Note 6)	PD	1.7 13.6	mW/°C	
	(Note 5)		113	2011/	
Thermal Resistance, Junction to Ambient	(Note 6)	R _{0JA}	73	°C/W	
Operating and Storage Temperature Range		TJ, T _{STG}	-55 to +150	°C	

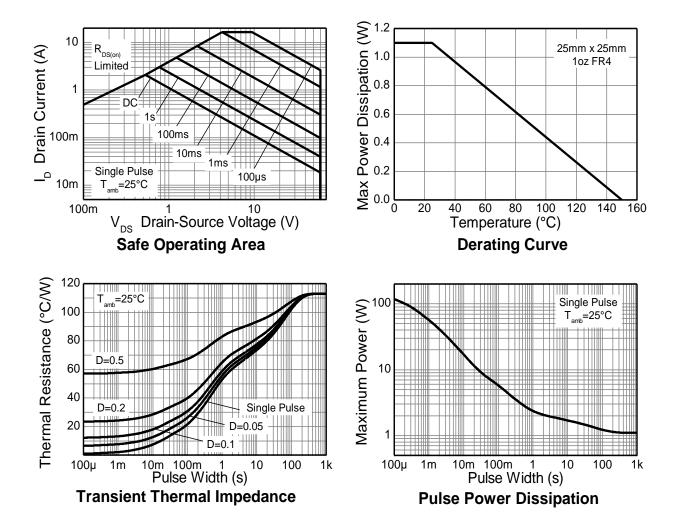
Notes: 5. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.

6. Same as Note 5, except the device is measured at t \leq 10 sec.

7. Same as Note 5, except the device is pulsed with D = 0.02 and pulse width 300 µs. The pulse current is limited by the maximum junction temperature.



Thermal Characteristics





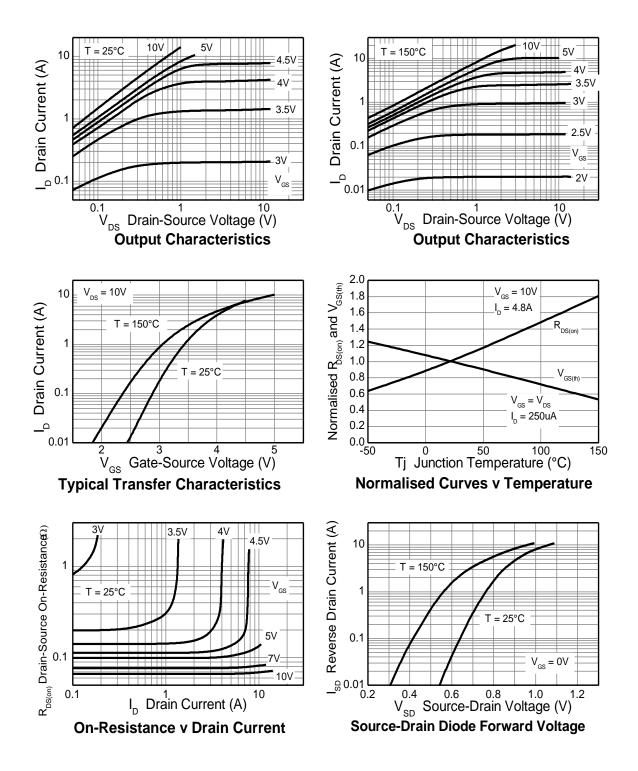
Electrical Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test	Condition
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	60	—		V	$I_D = 250 \mu A, V_{GS} = 0 V$	
Zero Gate Voltage Drain Current	I _{DSS}	_	—	0.5	μA	$V_{DS} = 60V, V_{GS} = 0V$	
Gate-Source Leakage	IGSS	_	—	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS							
Gate Threshold Voltage	V _{GS(th)}	1.0	_		V	$I_D = 250 \mu A$, $V_{DS} = V_{GS}$	
Statia Drain Source On Begistenes (Note 8)	Denne		0.067	0.080	Ω	$V_{GS} = 10V, I_D = 4.8A$	
Static Drain-Source On-Resistance (Note 8)	R _{DS(ON)}	_	0.100	0.150		V_{GS} = 4.5V, I_D	= 4.2A
Forward Transconductance (Notes 8 & 9)	g _{fs}		6.6		S	V _{DS} = 15V, I _D = 4.8A	
Diode Forward Voltage (Note 8)	V _{SD}	_	0.88	1.2	V	$I_{S} = 4A, V_{GS} = 0V, T_{J} = +25^{\circ}C$	
Reverse Recovery Time (Note 9)	t _{rr}	_	19.2	_	ns	$I_F = 1.4A, di/dt = 100A/\mu s,$ $T_J = +25^{\circ}C$	
Reverse Recovery Charge (Note 9)	Qrr	_	30.3	_	nC		
DYNAMIC CHARACTERISTICS (Note 9)							
Input Capacitance	Ciss	_	459	_	pF	V _{DS} = 40V, V _{GS} = 0V f = 1MHz	
Output Capacitance	Coss		44.2		pF		
Reverse Transfer Capacitance	Crss		24.1	_	pF		
Total Gate Charge (Note 10)	Qg	_	3.7	_	nC	$V_{GS} = 4.5V$	
Total Gate Charge (Note 10)	Qg	_	5.8		nC	$V_{GS} = 10V$ $V_{DS} = 30V$ $V_{D} = 1.4A$	
Gate-Source Charge (Note 10)	Q _{gs}	_	1.4	_	nC		
Gate-Drain Charge (Note 10)	Q _{gd}		1.9		nC		
Turn-On Delay Time (Note 10)	t _{D(on)}		2.6		ns	ns $V_{DD} = 30V, V_{GS} = 10V$	
Turn-On Rise Time (Note 10)	tr		2.1		ns		
Turn-Off Delay Time (Note 10)	t _{D(off)}		12.3	_	ns		
Turn-Off Fall Time (Note 10)	t _f	_	4.6		ns		

 8. Measured under pulsed conditions. Pulse width ≤ 300µs; duty cycle ≤ 2%.
9. For design aid only, not subject to production testing.
10. Switching characteristics are independent of operating junction temperatures. Notes:

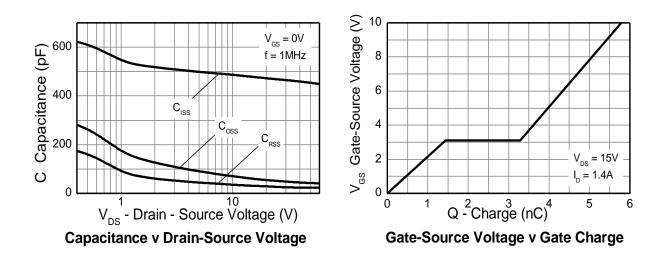


Typical Characteristics

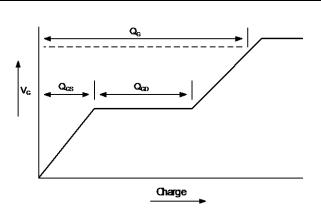




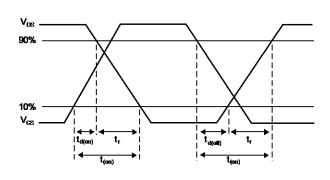
Typical Characteristics (cont.)



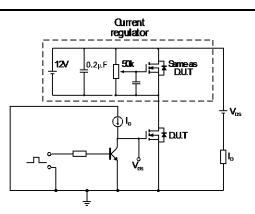
Test Circuits



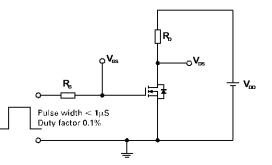




Switching time waveforms



Gate charge test circuit

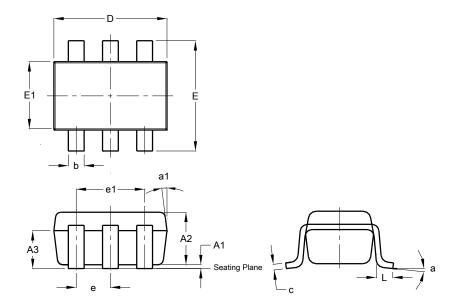


Switching time test circuit



Package Outline Dimensions

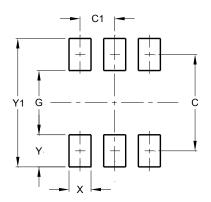
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for latest version.



SOT26						
Dim	Min	Max	Тур			
A1	0.013	0.10	0.05			
A2	1.00	1.30	1.10			
A3	0.70	0.80	0.75			
b	0.35	0.50	0.38			
С	0.10	0.20	0.15			
D	2.90	3.10	3.00			
е	-	-	0.95			
e1	-	-	1.90			
E	2.70	3.00	2.80			
E1	1.50	1.70	1.60			
L	0.35	0.55	0.40			
а	-	-	8°			
a1	-	-	7°			
All Dimensions in mm						

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)		
С	2.40		
C1	0.95		
G	1.60		
Х	0.55		
Y	0.80		
Y1	3.20		



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